

RFP2N15-VB Datasheet

N-Channel 200 V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	200				
$R_{DS(on)}(\Omega)$	V _{GS} = 10 V 0. 91				
Q _g (Max.) (nC)	13				
Q _{gs} (nC)	3.0				
Q _{gd} (nC)	7.9				
Configuration	Single				

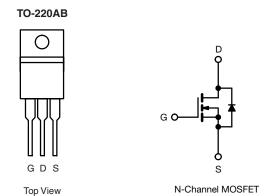
FEATURES



- Trench Power MOSFET
- 175 °C Junction Temperature
- PWM Optimized
- 100 % R_a Tested
- Compliant to RoHS Directive 2002/95/EC

APPLICATIONS

· Primary Side Switch



ABSOLUTE MAXIMUM RATINGS (To	c = 25 °C, un	less otherwis	se noted)			
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V_{DS}	200	V	
Gate-Source Voltage			V_{GS}	± 20	¬	
Continuous Drain Current	V _{GS} at 10 V	T _C = 25 °C		5.0		
Continuous Drain Current	V _{GS} at 10 V	T _C = 100 °C	I _D	4.0	Α	
Pulsed Drain Current ^a			I _{DM}	20		
Linear Derating Factor				0.33	W/°C	
Linear Derating Factor (PCB Mount) e				0.020	VV/ C	
Single Pulse Avalanche Energy b			E _{AS}	161	mJ	
Repetitive Avalanche Current ^a			I _{AR}	4.8	Α	
Repetitive Avalanche Energy ^a			E _{AR}	4.2	mJ	
Maximum Power Dissipation $T_C = 25 ^{\circ}C$		Б	42	W		
Maximum Power Dissipation (PCB mount) e	T _A = 25 °C		P_{D}	2.5		
Peak Diode Recovery dV/dt ^c			dV/dt	5.0	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	-55 to +150		
Soldering Recommendations (Peak temperature)	l for	for 10 s		260	°C	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. $V_{DD}=50~V$, starting $T_J=25~^{\circ}C$, L=14~mH, $R_g=25~\Omega$, $I_{AS}=4.8~A$ (see fig. 12). c. $I_{SD}\leq5.2~A$, $I_{AS}=4.8~A$ (see fig. 12).

- d. 1.6 mm from case.
- e. When mounted on 1" square PCB (FR-4 or G-10 material).



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R _{thJA}	-	-	110	
Maximum Junction-to-Ambient (PCB mount) ^a	R _{thJA}	-	-	50	°C/W
Maximum Junction-to-Case (Drain)	R _{thJC}	-	-	3.0	

Note

a. When mounted on 1" square PCB (FR-4 or G-10 material).

PARAMETER	SYMBOL	TES	MIN.	TYP.	MAX.	UNIT	
Static				l		I.	•
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} :	= 0 V, I _D = 250 μA	200	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	ce to 25 °C, I _D = 1 mA	-	0.29	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}		V _{GS} = ± 20 V	-	-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}		= 200 V, V _{GS} = 0 V V, V _{GS} = 0 V, T _J = 125 °C	-	-	25 250	μΑ
Drain-Source On-State Resistance	R _{DS(on)}	$V_{GS} = 100 \text{ V}$	$I_D = 2.9 \text{ A}^b$	_	0.91	-	Ω
Forward Transconductance	9 _{fs}		= 50 V, I _D = 2.9 A b	1.7	-	_	S
Dynamic	91S	1 105 -	- 00 V, ID = 2.0 / C	1.,			
Input Capacitance	C _{iss}		V 0V	_	185	_	
Output Capacitance	C _{oss}	-	$V_{GS} = 0 V$, $V_{DS} = 25 V$,	-	100	-	pF
Reverse Transfer Capacitance	C _{rss}	f = 1	.0 MHz, see fig. 5	-	30	-	
Total Gate Charge	Qq			-	-	13.0	
Gate-Source Charge		V _{GS} = 10 V	$I_D = 4.8 \text{ A}, V_{DS} = 160 \text{ V},$	-	-	3.0	nC
Gate-Drain Charge	•		see lig. 6 and 15 ~			7.9	1
Turn-On Delay Time				-	7.2	-	
Rise Time	t _r	- 7.2 r V _{DD} = 100 V, I _D = 4.8 A, - 22		-	7		
Turn-Off Delay Time	t _{d(off)}	$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	19	-	ns		
Fall Time	t _f			-	13	-	
Internal Drain Inductance	L _D	Between lead		-	4.5	-	-11
Internal Source Inductance	L _S			-	- nH		
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	showing the	MOSFET symbol showing the		-	4.8	
Pulsed Diode Forward Current ^a	I _{SM}	integral revers p - n junction	+ 	-	-	19	A
Body Diode Voltage	V _{SD}	T _J = 25 °C	, I _S = 4.8 A, V _{GS} = 0 V ^b	-	-	1.8	V
Body Diode Reverse Recovery Time	t _{rr}	T 05 %C !	40 A -11/-14 - 400 A / - b	-	150	300	ns
Body Diode Reverse Recovery Charge	Q _{rr}	$T_J = 25 ^{\circ}\text{C}$, $I_F = 4.8 \text{A}$, $dI/dt = 100 \text{A/µs}^{\text{b}}$ - 0.91		1.8	μC		
Forward Turn-On Time	t _{on}	Intrinsic tu	ırn-on time is negligible (turn	-on is dor	minated b	y L _S and	L _D)

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width \leq 300 μs ; duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

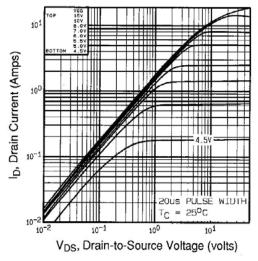


Fig. 1 - Typical Output Characteristics, $T_C = 25$ °C

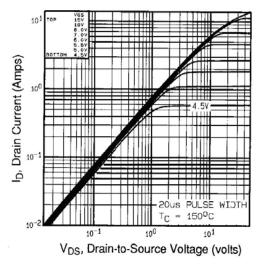


Fig. 2 - Typical Output Characteristics, $T_C = 150$ °C

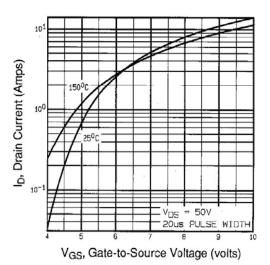


Fig. 3 - Typical Transfer Characteristics

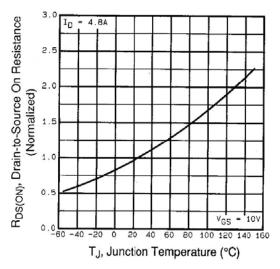


Fig. 4 - Normalized On-Resistance vs. Temperature



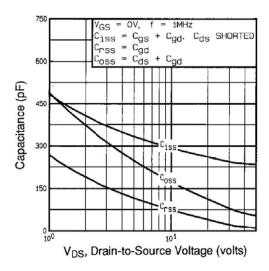


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

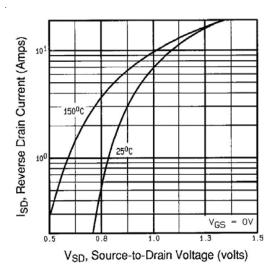


Fig. 7 - Typical Source-Drain Diode Forward Voltage

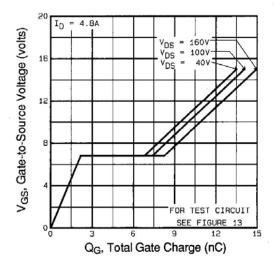


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

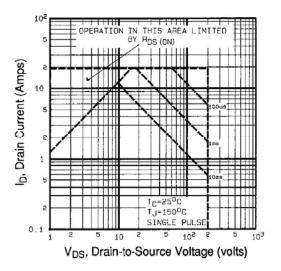


Fig. 8 - Maximum Safe Operating Area



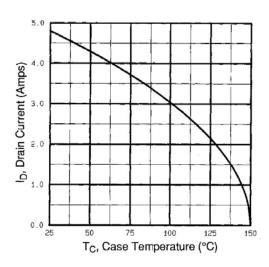


Fig. 9 - Maximum Drain Current vs. Case Temperature

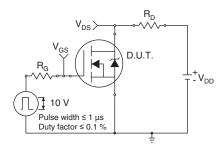


Fig. 10a - Switching Time Test Circuit

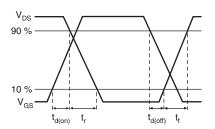


Fig. 10b - Switching Time Waveforms

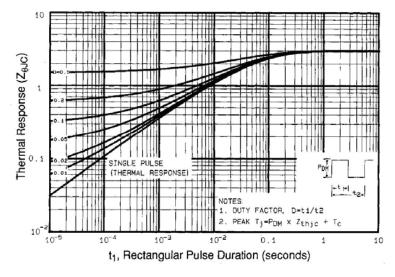


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



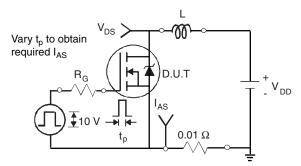


Fig. 12a - Unclamped Inductive Test Circuit

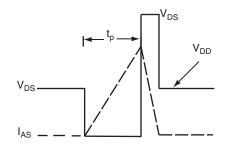


Fig. 12b - Unclamped Inductive Waveforms

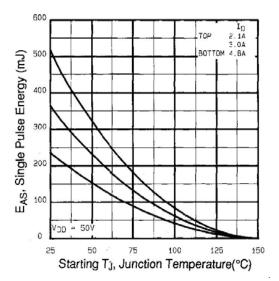


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

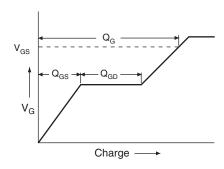


Fig. 13a - Basic Gate Charge Waveform

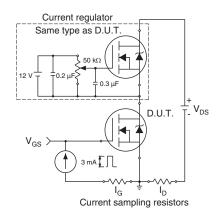
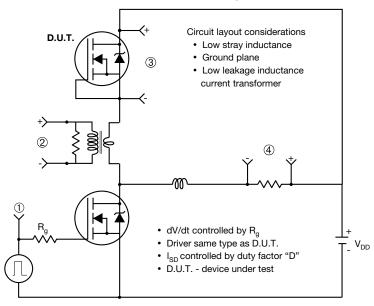


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



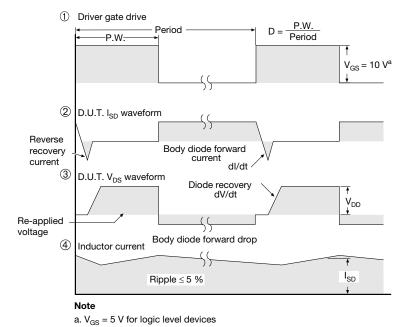
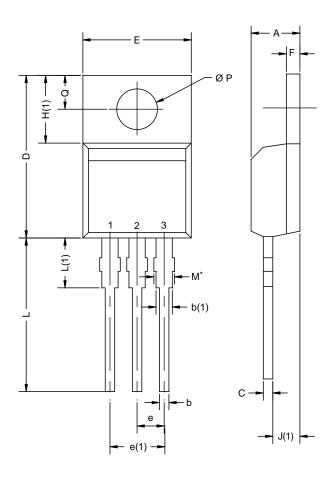


Fig. 14 - For N-Channel



TO-220AB



	MILLIMETERS		INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
Α	4.25	4.65	0.167	0.183
b	0.69	1.01	0.027	0.040
b(1)	1.20	1.73	0.047	0.068
С	0.36	0.61	0.014	0.024
D	14.85	15.49	0.585	0.610
Е	10.04	10.51	0.395	0.414
е	2.41	2.67	0.095	0.105
e(1)	4.88	5.28	0.192	0.208
F	1.14	1.40	0.045	0.055
H(1)	6.09	6.48	0.240	0.255
J(1)	2.41	2.92	0.095	0.115
L	13.35	14.02	0.526	0.552
L(1)	3.32	3.82	0.131	0.150
ØР	3.54	3.94	0.139	0.155
Q	2.60	3.00	0.102	0.118
ECN: X12- DWG: 547	0208-Rev. N, 1	08-Oct-12		

Notes

 $^{^{\}star}$ M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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